Machine Learning Algorithms for Cybersecurity in IoT Networks

Guest Editors:

Dr. Adel Abusitta
Department of Computer Engineering and Software Engineering, Polytechnique Montreal, Montreal, QC H3T 1J4, Canada

Dr. Ziad Kobti
School of Computer Science, University of Windsor, Windsor, ON N9B 3P4, Canada

Deadline for manuscript submissions:
15 September 2024

Message from the Guest Editors

This Special Issue will focus on the application of machine learning algorithms for cybersecurity in IoT networks. We will explore the latest research and developments in this rapidly evolving field. Some of the topics that will be covered include:

- Machine learning-based intrusion detection systems for IoT networks;
- Deep learning techniques for malware detection in IoT networks;
- Use of artificial intelligence for anomaly detection in IoT networks;
- Machine learning-based approaches for secure communication in IoT networks;
- Detection and prevention of DDoS attacks using machine learning in IoT networks;
- Machine learning techniques for risk assessment in IoT networks;
- Secure data analytics in IoT networks using machine learning algorithms;
- Use of machine learning algorithms for IoT network security monitoring;
- Deep learning-based approaches for detecting zero-day attacks in IoT networks;
- Machine learning-based techniques for secure authentication in IoT networks.

mdpi.com/si/169487

Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.
High Visibility: indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, Ei Compendex and other databases.
Journal Rank: JCR - Q2 (*Physics, Applied*) / CiteScore - Q2 (*Control and Systems Engineering*)

Contact Us